



Docket No.: SON-2810
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Yoshitaka Kayukawa et al.

Application No.: 10/647,217

Confirmation No.: 1901

Filed: August 26, 2003

Art Unit: 2138

For: SEMICONDUCTOR INTEGRATED CIRCUIT
AND METHOD FOR TESTING SAME

Examiner: D. B. Gandhi

AMENDMENT IN RESPONSE TO NON-FINAL OFFICE ACTION

MS Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

INTRODUCTORY COMMENTS

In response to the Office Action dated February 24, 2006, please amend the above-identified U.S. patent application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 10 of this paper.

Remarks/Arguments begin on page 10 of this paper.

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